

### **General Description**

The WSD3039DN56 uses advanced trench technology to provide excellent  $R_{DS(ON)}$ , low gate charge and operation with gate voltages as low as 4.5V. This device is suitable for use as a Battery protection or in other Switching application.

The WSD3039DN56 meet the RoHS and Green Product requirement, 100%  $E_{AS}$  guaranteed with full function reliability approved.

#### **Features**

- Advanced high cell density Trench technology
- Super Low Gate Charge
- 100% E<sub>AS</sub> Guaranteed
- Green Device Available

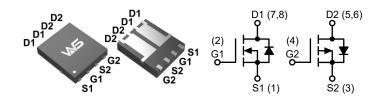
### **Product Summery**

BV <sub>DSS</sub>	R <sub>DS(ON)</sub>	I <sub>D</sub>
30V	14mΩ	20A
-30V	24mΩ	-16A

### **Applications**

- Wireless charging
- Boost driver.
- Brushless motor

### **DFN5X6-8L Pin Configuration**



## **Absolute Maximum Ratings** (T<sub>C</sub>=25°C, Unless Otherwise Noted)

Compleal	Downworks.	Rat	Rating		
Symbol	Parameter	N-Channel	P-Channel	Units	
V <sub>DS</sub>	Drain-Source Voltage	30	-30	V	
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V	
I <sub>D</sub> @T <sub>C</sub> =25°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	20	-16		
I <sub>D</sub> @T <sub>A</sub> =100°C	Continuous Drain Current, V <sub>GS</sub> @ 10V <sup>1</sup>	10	-8	A	
I <sub>DM</sub>	Pulsed Drain Current <sup>2</sup>	52	-45		
E <sub>AS</sub>	Single Pulse Avalanche Energy <sup>3</sup>	22	45	mJ	
I <sub>AS</sub>	Avalanche Current	21	-30	А	
P <sub>D</sub> @T <sub>A</sub> =25°C	Power Dissipation <sup>4</sup>	18	18	W	
T <sub>STG</sub>	Storage Temperature Range		-55 to 150	°C	
T <sub>J</sub>	Operating Junction Temperature Range		-55 to 150	C	

#### **Thermal Data**

Symbol Parameter		Rating	Units
$R_{ heta JA}$	R <sub>θJA</sub> Thermal Resistance, Junction-to-Ambient <sup>1</sup>		°C/W
$R_{ heta JC}$	Thermal Resistance, Junction-to-Case <sup>1</sup> ,(t<=10sec)	5.0	C/VV



## N-Channel Electrical Characteristics (T<sub>J</sub>=25°C, Unless Otherwise Noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250μA	30			V
В	2 2	V <sub>GS</sub> =10V , I <sub>D</sub> =10A		14	23	0
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A		19	28	mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_D=250\mu A$	1.0	1.6	2.5	V
	Drain Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1.0	
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =55°C			5.0	μA
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V			±100	nA
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =10A		16		S
$R_{g}$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , <i>f</i> =1.0MHz		2.5	5	Ω
$Q_g$	Total Gate Charge (4.5V)	- V <sub>DS</sub> =20V , V <sub>GS</sub> =4.5V ,		7.2		
$Q_gs$	Gate-Source Charge			1.4		nC
$Q_{gd}$	Gate-Drain Charge	I <sub>D</sub> =10A		2.2		
T <sub>d(on)</sub>	Turn-On Delay Time			4.1		
T <sub>r</sub>	Rise Time	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V ,		9.8		
$T_{d(off)}$	Turn-Off Delay Time	$R_G=3.3\Omega$ , $I_D=5A$		15.5		ns
T <sub>f</sub>	Fall Time			6.0		
C <sub>iss</sub>	Input Capacitance			572		
C <sub>oss</sub>	Output Capacitance	V <sub>DS</sub> =15V , V <sub>GS</sub> =0V , <i>f</i> =1.0MHz		81		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			65		

### **Diode Characteristics**

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
I <sub>S</sub>	Continuous Source Current 1,5	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			10	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =1A , T <sub>J</sub> =25°C			1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width  $\leq 300 us$  , duty cycle  $\leq 2\%.$
- 3. The E\_{AS} data shows Max. rating . The test condition is  $V_{DD}$ =25V,  $V_{GS}$ =10V, L=0.1mH,  $I_{AS}$ =10A
- 4. The power dissipation is limited by 150°C junction temperature.
- 5. The data is theoretically the same as  $\ensuremath{I_D}$  and  $\ensuremath{I_{DM}}$  , in real applications , should be limited by total power dissipation.



## P-Channel Electrical Characteristics (T<sub>J</sub>=25°C, Unless Otherwise Noted)

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =-250µA	-30			V
D		V <sub>GS</sub> =-10V , I <sub>D</sub> =-7A		24	31	mΩ
R <sub>DS(ON)</sub>	Static Drain-Source On-Resistance <sup>2</sup>	V <sub>GS</sub> =-4.5V , I <sub>D</sub> =-5A		36	52	11177
V <sub>GS(th)</sub>	Gate Threshold Voltage	$V_{GS}=V_{DS}$ , $I_{D}=-250\mu A$	-1.0		-2.5	V
	Drain-Source Leakage Current	V <sub>DS</sub> =-24V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C			1.0	
I <sub>DSS</sub>	Diani-Source Leakage Current	$V_{DS}$ =-24V , $V_{GS}$ =0V , $T_{J}$ =55°C			5.0	μΑ
I <sub>GSS</sub>	Gate-Source Leakage Current	$V_{GS}$ =±20V , $V_{DS}$ =0V			±100	nA
g <sub>fs</sub>	Forward Transconductance	V <sub>DS</sub> =-5V , I <sub>D</sub> =-7A		15		S
$R_{g}$	Gate Resistance	V <sub>DS</sub> =0V , V <sub>GS</sub> =0V , <i>f</i> =1.0MHz		15	30	Ω
$Q_g$	Total Gate Charge (-4.5V)	V <sub>DS</sub> =-20V , V <sub>GS</sub> =-4.5V ,		9.8		
$Q_{gs}$	Gate-Source Charge			2.2		nC
$Q_{gd}$	Gate-Drain Charge	1 <sub>D</sub> =-7A		3.4		
T <sub>d(on)</sub>	Turn-On Delay Time			16.4		
T <sub>r</sub>	Rise Time	$V_{DD}$ =-15V , $V_{GS}$ =-10V ,		20.2		
$T_{d(off)}$	Turn-Off Delay Time	$R_G=3.3\Omega$ , $I_D=-5A$		55		ns
T <sub>f</sub>	Fall Time			10		
C <sub>iss</sub>	Input Capacitance			930		
C <sub>oss</sub>	Output Capacitance	nce V <sub>DS</sub> =-15V , V <sub>GS</sub> =0V , f=1.0MHz 148		148		pF
C <sub>rss</sub>	Reverse Transfer Capacitance			115		

### **Diode Characteristics**

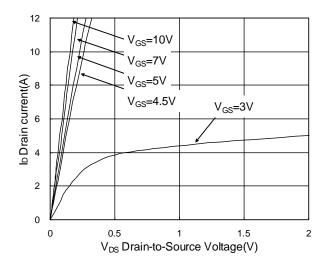
Symbol	Parameter	Conditions	Min.	Тур.	Max.	Units
I <sub>S</sub>	Continuous Source Current 1,5	V <sub>G</sub> =V <sub>D</sub> =0V , Force Current			-8	Α
V <sub>SD</sub>	Diode Forward Voltage <sup>2</sup>	V <sub>GS</sub> =0V , I <sub>S</sub> =-1A , T <sub>J</sub> =25°C			-1.2	V

#### Note:

- 1. The data tested by surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2OZ copper.
- 2. The data tested by pulsed , pulse width  $\leq$  300us , duty cycle  $\leq$  2%.
- 3. The E $_{AS}$  data shows Max. rating . The test condition is  $V_{DD}$ =-25V,  $V_{GS}$ =-10V, L=0.1mH,  $I_{AS}$ =-10A
- 4. The power dissipation is limited by 150°C junction temperature.
- 5. The data is theoretically the same as  $\ensuremath{I_D}$  and  $\ensuremath{I_{DM}}$  , in real applications , should be limited by total power dissipation.



## **N-Channel Typical Characteristics**



**Fig.1 Typical Output Characteristics** 

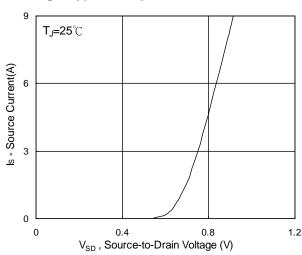


Fig.3 Forward Characteristics Of Reverse

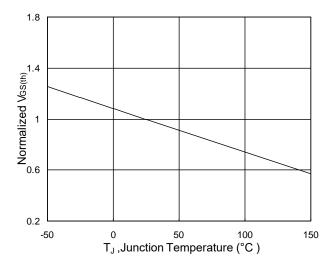


Fig.5 Normalized V<sub>GS(th)</sub> v.s T<sub>J</sub>

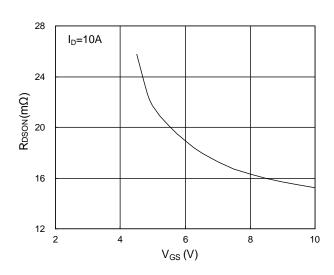


Fig.2 On-Resistance v.s Gate-Source

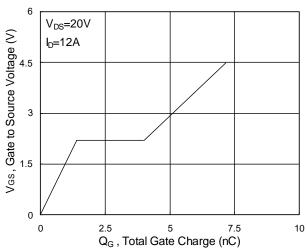


Fig.4 Gate-Charge characteristics

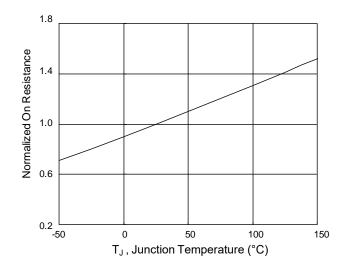
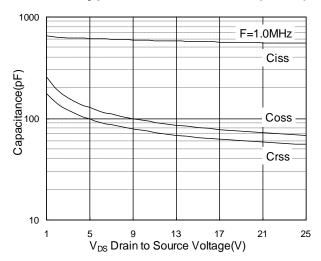


Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>



## **N-Channel Typical Characteristics (Cont.)**



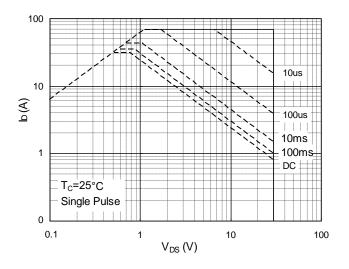


Fig.7 Capacitance

Fig.8 Safe Operating Area

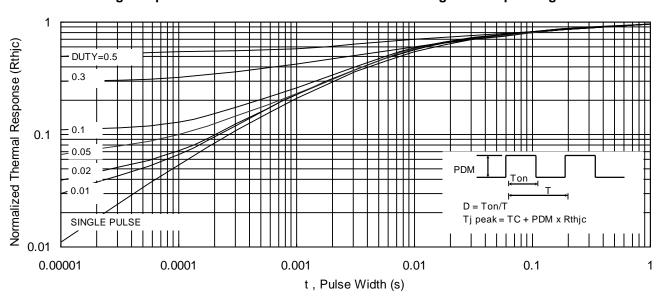


Fig.9 Normalized Maximum Transient Thermal Impedance

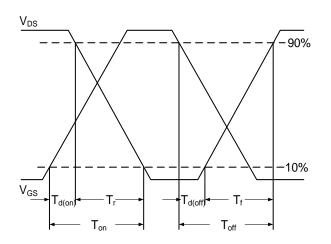


Fig.10 Switching Time Waveform

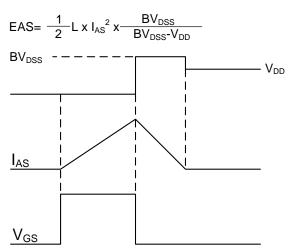


Fig.11 Unclamped Inductive Waveform



## **P-Channel Typical Characteristics**

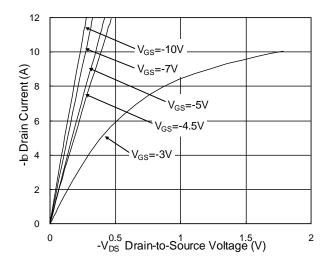


Fig.1 Typical Output Characteristics

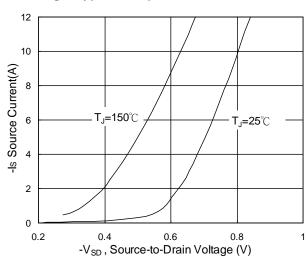


Fig.3 Forward Characteristics Of Reverse

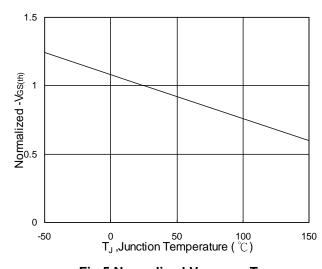


Fig.5 Normalized  $V_{\text{GS(th)}}$  v.s  $T_{\text{J}}$ 

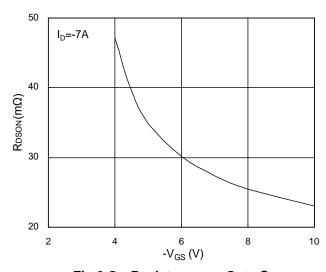


Fig.2 On-Resistance v.s Gate-Source

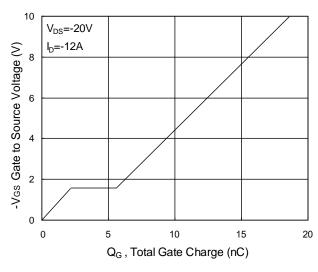


Fig.4 Gate-Charge Characteristics

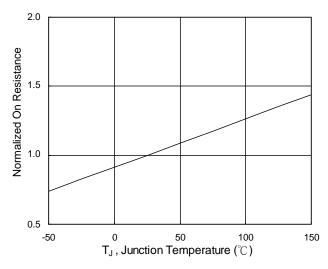
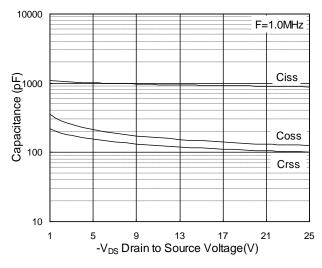


Fig.6 Normalized R<sub>DSON</sub> v.s T<sub>J</sub>



## P-Channel Typical Characteristics (Cont.)



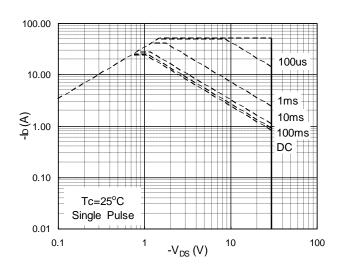


Fig.7 Capacitance

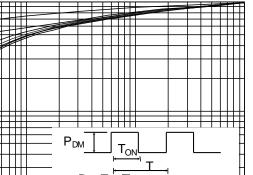


Fig.8 Safe Operating Area

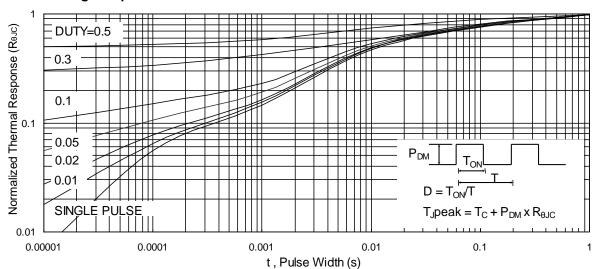
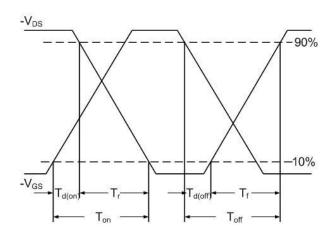


Fig.9 Normalized Maximum Transient Thermal Impedance





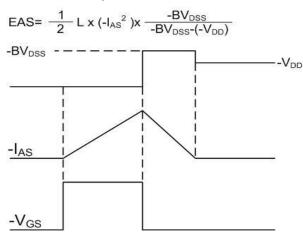
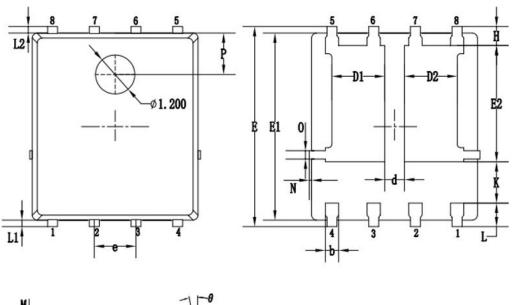
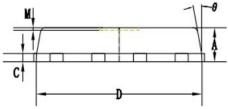


Fig.11 Unclamped Inductive Waveform



# **Packaging information**





OVMDOLO		MILLIMETERS			
SYMBOLS	MIN.	NOM.	MAX.		
Α	0.90	1.05	1.20		
b	0.35	0.40	0.50		
С	0.20	0.25	0.35		
D	4.90	5.05	5.20		
D1/D2	1.51	1.61	1.71		
d	0.50	0.60	0.70		
E	6.00	6.15	6.30		
E1	5.60	5.75	5.90		
E2	3.47	3.57	3.67		
е		1.27 BSC.			
Н	0.48	0.58	0.68		
K	1.17	1.27	1.37		
L	0.64	0.74	0.84		
L1/L2		0.20 REF.			
θ	8°	10°	12°		
M	0.08 REF.				
N	0	-	0.15		
0	0.25 REF.				
Р	1.28 REF.				



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